

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/687,662 SAWAOKA, HIDEO	
		Examiner Johnny H. Hoang	Art Unit 3747	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,125,322	09-2000	Bischof et al.	701/114
	B	US-			
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	OBD II Diagnostic Tester , 2000 Actron Manufacturing Co.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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